

TO-247 Plastic-Encapsulate MOSFETs

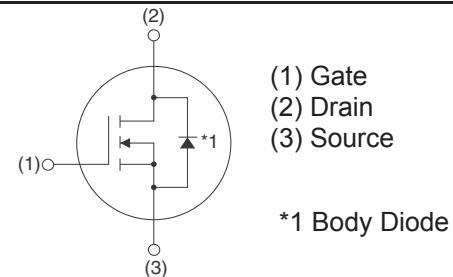
Features

- Low on-resistance
- Fast switching speed
- Fast reverse recovery
- Easy to parallel
- Simple to drive
- Pb-free lead plating ; RoHS compliant
- N-channel SiC power MOSFET

MECHANICAL DATA

- Case style:TO-247 molded plastic
- Mounting position:any

● Inner circuit



● Packaging specifications

Type	Packing	Tube
	Basic ordering unit (pcs)	30
	Taping code	C11
	Marking	SCT3022KL

MAXIMUM RATINGS AND CHARACTERISTICS

@ 25°C Ambient Temperature (unless otherwise noted)

Parameter	Symbol	Value	Unit
Drain - Source voltage	V _{DSS}	1200	V
Continuous drain current	T _c = 25°C	I _D ^{*1}	A
	T _c = 100°C	I _D ^{*1}	A
Pulsed drain current	I _{D,pulse} ^{*2}	237	A
Gate - Source voltage	V _{GSS}	-4 to 22	V
Gate-Source Surge Voltage	V _{GSS,surge}	-4 to 22	V
Recommended Drive Voltage	V _{GS,op}	0 / 18	V
Junction temperature	T _j	175	°C
Range of storage temperature	T _{stg}	-55 to +175	°C

V _{DSS}	1200V
R _{DS(on)} (Typ.)	22mΩ
I _D	95A
P _D	427W

MOSFET ELECTRICAL CHARACTERISTICS T_A = 25 °C unless otherwise specified

Parameter	Symbol	Conditions	Values			Unit
			Min.	Typ.	Max.	
Drain - Source breakdown voltage	V _{(BR)DSS}	V _{GS} = 0V, I _D = 1mA	1200	-	-	V
Zero gate voltage drain current	I _{DSS}	V _D = 1200V, V _{GS} = 0V T _j = 25°C T _j = 150°C	-	1	1	0.µA
Gate - Source leakage current	I _{GSS+}	V _{GS} = +22V, V _D = 0V	-	-	100	nA
Gate - Source leakage current	I _{GSS-}	V _{GS} = -4V, V _D = 0V	-	-	100-	nA
Gate threshold voltage	V _{GS(th)}	V _D = 10V, I _D = 18.2mA	2.7	-	5.6	V
Static drain - source on - state resistance	R _{DS(on)} ^{*3}	V _{GS} = 18V, I _D = 36A T _j = 25°C T _j = 125°C	-	22	28.6	mΩ
Gate input resistance	R _G	f = 1MHz, open drain	-	4	-	Ω
Thermal resistance, junction - case	R _{thJC}		-	0.27	0.35	°C/W

● Example of acceptable V_{gs} waveform



● Electrical characteristics ($T_a = 25^\circ C$)

Parameter	Symbol	Conditions	Values			Unit
			Min.	Typ.	Max.	
Transconductance	g_{fs}^{*3}	$V_{DS} = 10V, I_D = 36A$	-	14.2	-	S
Input capacitance	C_{iss}	$V_{GS} = 0V$ $V_{DS} = 800V$ $f = 1MHz$	-	2879	-	pF
Output capacitance	C_{oss}		-	237	-	
Reverse transfer capacitance	C_{rss}		-	108	-	
Effective output capacitance, energy related	$C_{o(er)}$	$V_{GS} = 0V$ $V_{DS} = 0V$ to $600V$	-	213	-	pF
Turn - on delay time	$t_{d(on)}^{*3}$	$V_{DD} = 400V, I_D = 18A$ $V_{GS} = 18V/0V$ $R_L = 22\Omega$ $R_G = 0\Omega$	-	29	-	ns
Rise time	t_r^{*3}		-	44	-	
Turn - off delay time	$t_{d(off)}^{*3}$		-	67	-	
Fall time	t_f^{*3}		-	28	-	
Turn - on switching loss	E_{on}^{*3}	$V_{DD} = 600V, I_D = 36A$ $V_{GS} = 18V/0V$ $R_G = 0\Omega L = 250\mu H$ * E_{on} includes diode reverse recovery	-	632	-	μJ
Turn - off switching loss	E_{off}^{*3}		-	243	-	

● Gate Charge characteristics ($T_a = 25^\circ C$)

Parameter	Symbol	Conditions	Values			Unit
			Min.	Typ.	Max.	
Total gate charge	Q_g^{*3}	$V_{DD} = 600V$ $I_D = 36A$ $V_{GS} = 18V$	-	178	-	nC
Gate - Source charge	Q_{gs}^{*3}		-	40	-	
Gate - Drain charge	Q_{gd}^{*3}		-	80	-	
Gate plateau voltage	$V_{(plateau)}$	$V_{DD} = 600V, I_D = 36A$	-	9.6	-	V

*1 Limited only by maximum temperature allowed.

*2 PW $\leq 10\mu s$, Duty cycle $\leq 1\%$

*3 Pulsed

● Body diode electrical characteristics (Source-Drain) ($T_a = 25^\circ C$)

Parameter	Symbol	Conditions	Values			Unit
			Min.	Typ.	Max.	
Inverse diode continuous, forward current	I_S^{*1}	$T_c = 25^\circ C$	-	-	95	A
Inverse diode direct current, pulsed	I_{SM}^{*2}		-	-	237	A
Forward voltage	V_{SD}^{*3}	$V_{GS} = 0V, I_S = 36A$	-	3.2	-	V
Reverse recovery time	t_{rr}^{*3}	$I_F = 36A, V_R = 600V$ $di/dt = 1100A/\mu s$	-	28	-	ns
Reverse recovery charge	Q_{rr}^{*3}		-	175	-	nC
Peak reverse recovery current	I_{rrm}^{*3}		-	12	-	A

RATINGS AND CHARACTERISTIC CURVES

Fig.1 Power Dissipation Derating Curve

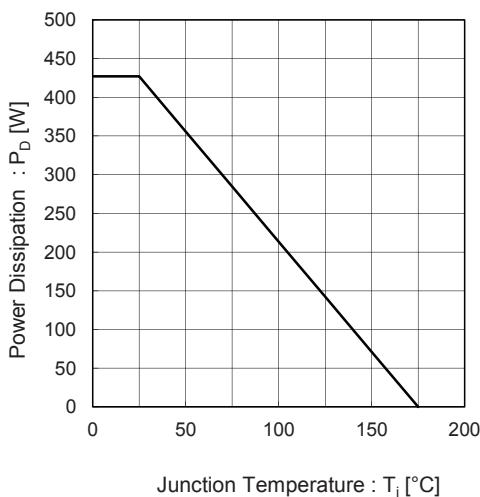


Fig.2 Maximum Safe Operating Area

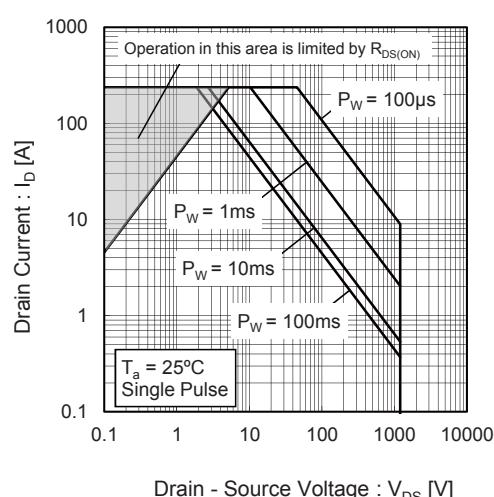


Fig.3 Typical Transient Thermal Resistance vs. Pulse Width

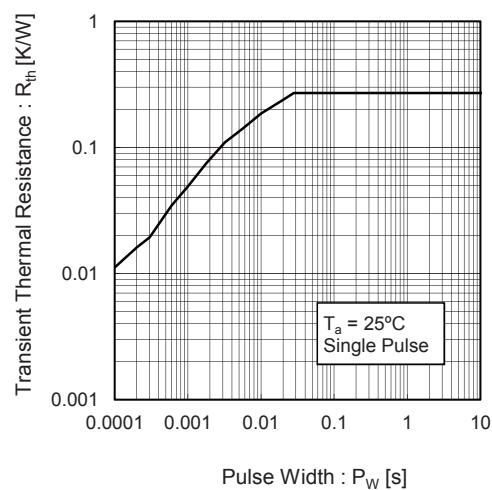


Fig.4 Typical Output Characteristics(I)

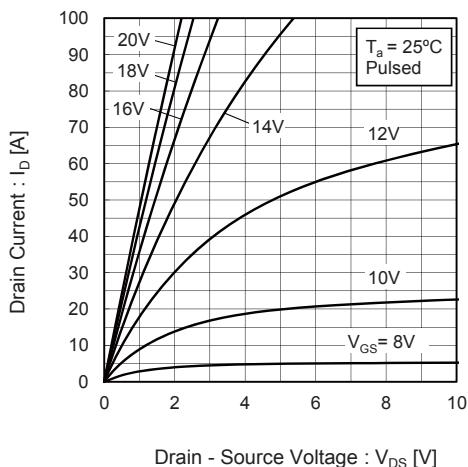


Fig.5 Typical Output Characteristics(II)

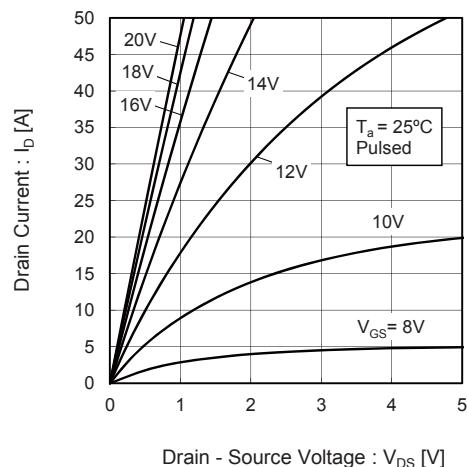


Fig.6 $T_j = 150^\circ\text{C}$ Typical Output Characteristics(I)

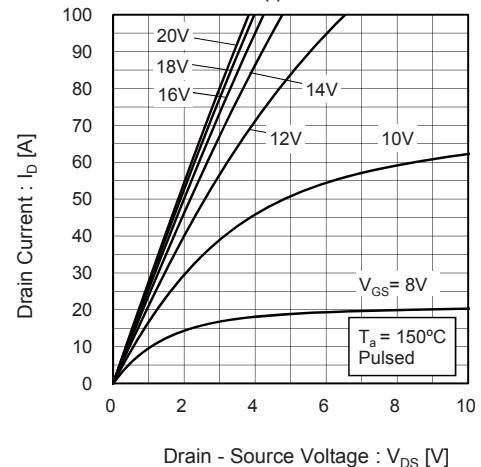


Fig.7 $T_j = 150^\circ\text{C}$ Typical Output Characteristics(II)

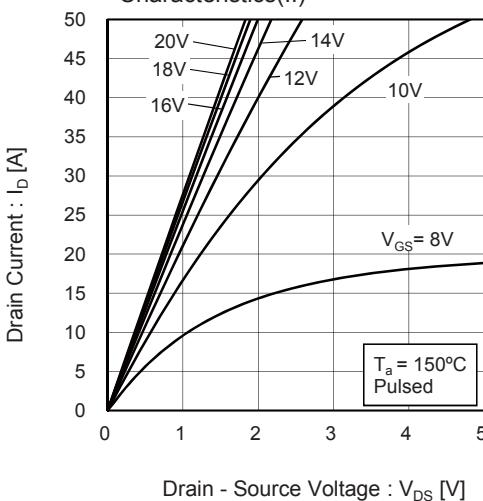


Fig.8 Typical Transfer Characteristics (I)

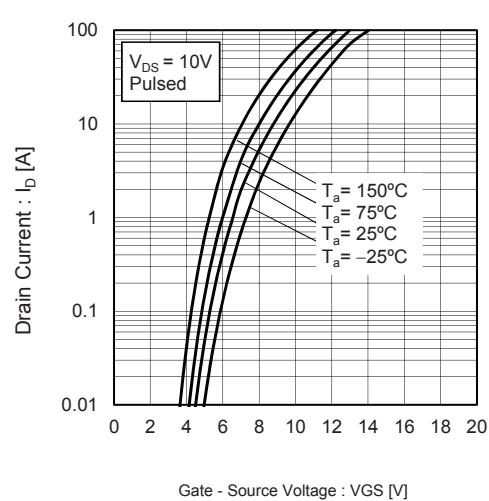
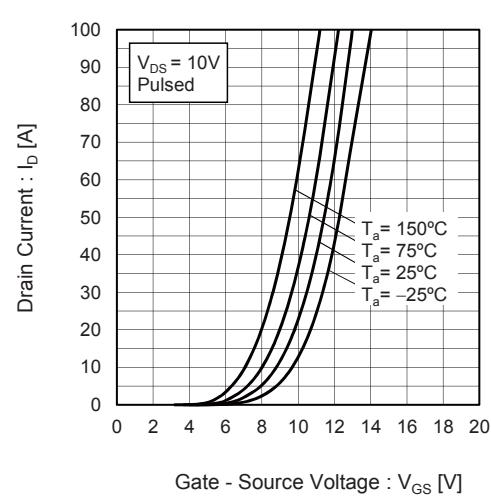


Fig.9 Typical Transfer Characteristics (II)



RATINGS AND CHARACTERISTIC CURVES

Fig.10 Gate Threshold Voltage vs. Junction Temperature

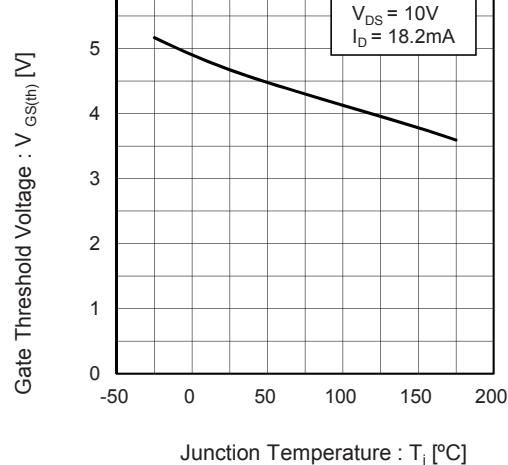


Fig.11 Transconductance vs. Drain Current

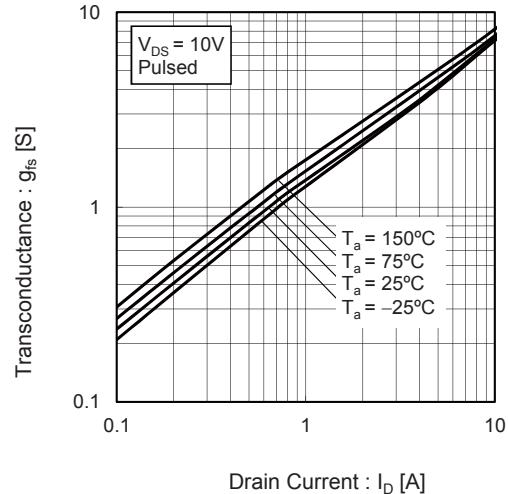


Fig.12 Static Drain - Source On - State Resistance vs. Gate - Source Voltage

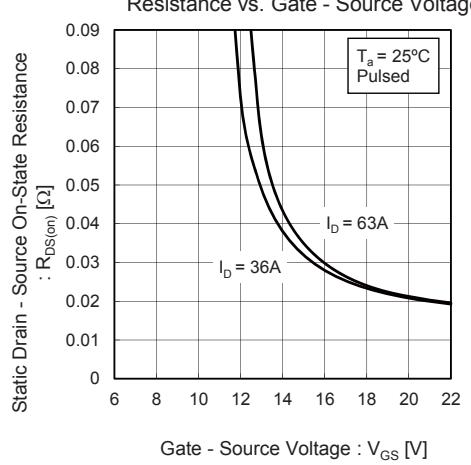


Fig.13 Static Drain - Source On - State Resistance vs. Junction Temperature

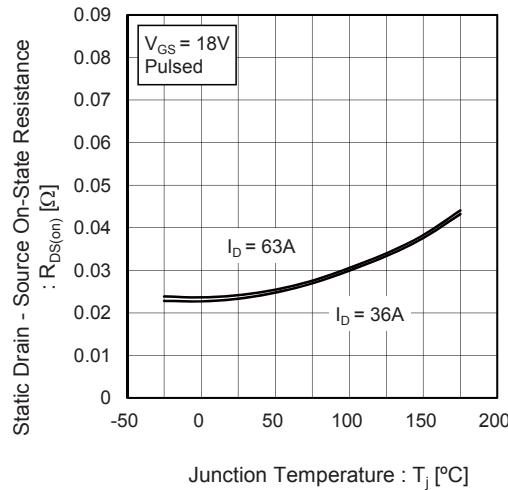


Fig.14 Static Drain - Source On - State Resistance vs. Drain Current

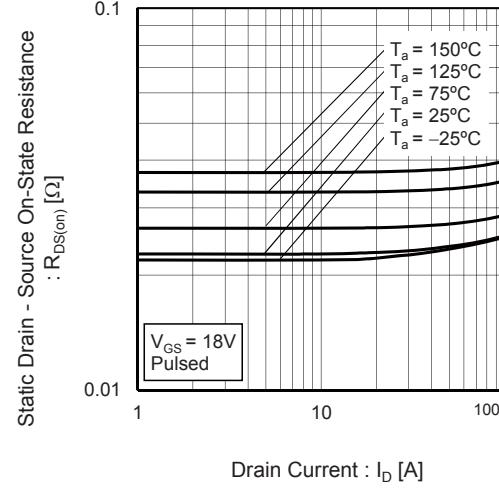


Fig.15 Typical Capacitance vs. Drain - Source Voltage

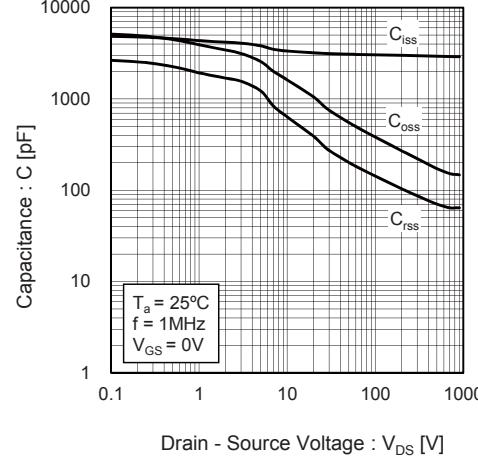


Fig.16 Coss Stored Energy

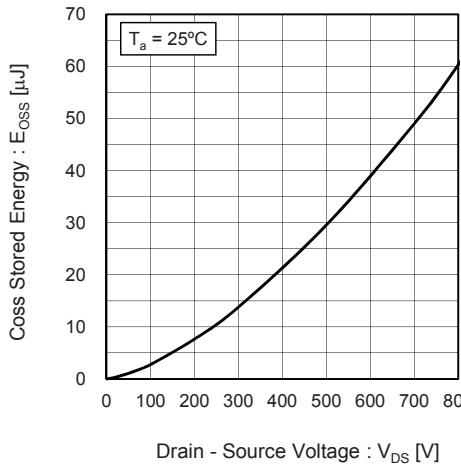


Fig.17 Switching Characteristics

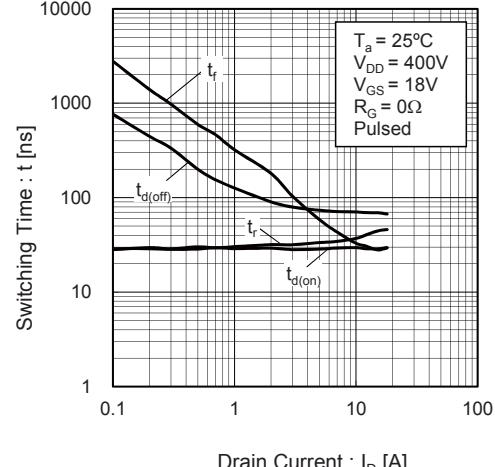
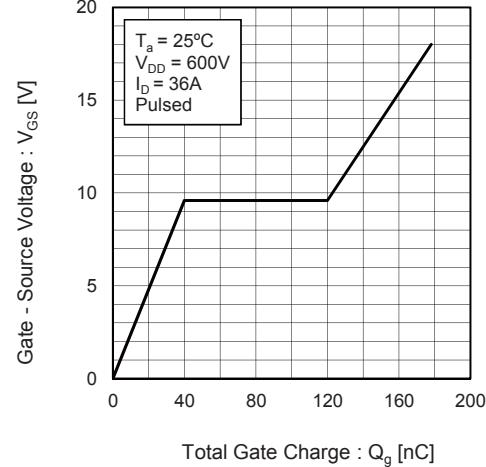


Fig.18 Dynamic Input Characteristics



RATINGS AND CHARACTERISTIC CURVES

Fig.19 Typical Switching Loss vs. Drain - Source Voltage

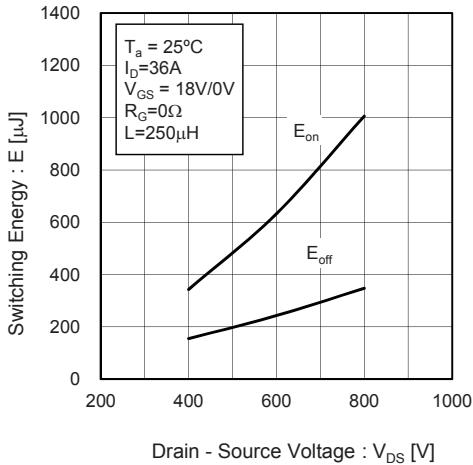


Fig.20 Typical Switching Loss vs. Drain Current

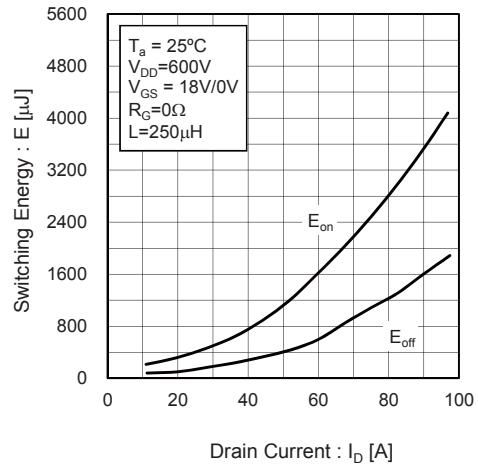


Fig.21 Typical Switching Loss vs. External Gate Resistance

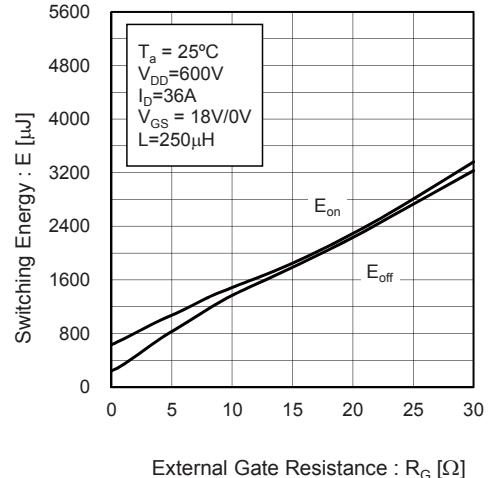


Fig.22 Inverse Diode Forward Current vs. Source - Drain Voltage

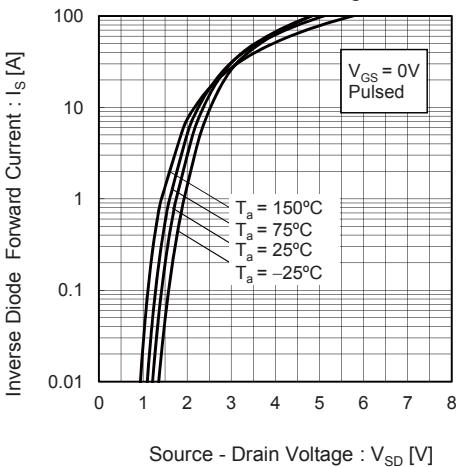
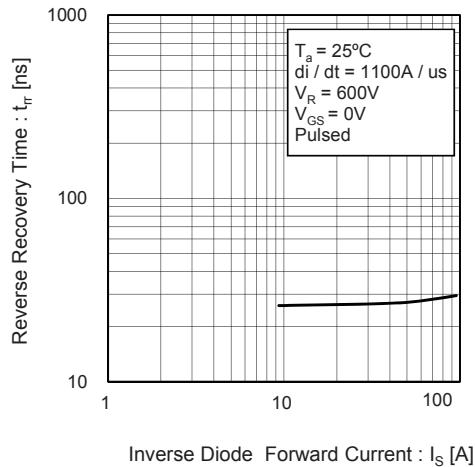


Fig.23 Reverse Recovery Time vs. Inverse Diode Forward Current



●Measurement circuits

Fig.1-1 Switching Time Measurement Circuit

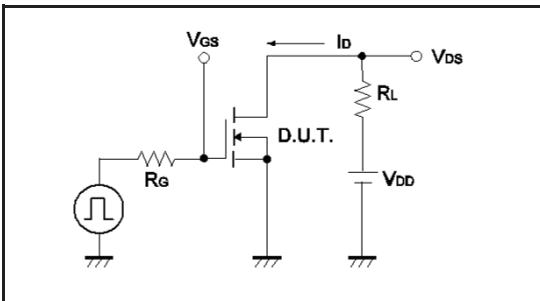


Fig.1-2 Switching Waveforms

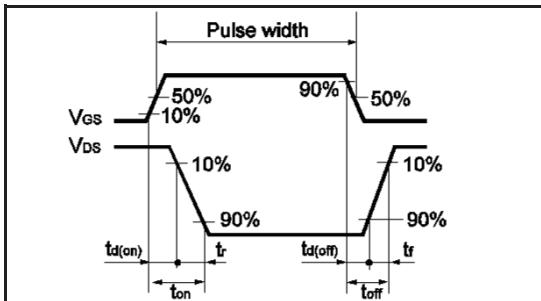


Fig.2-1 Gate Charge Measurement Circuit

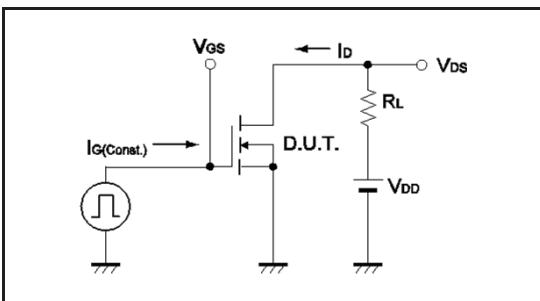


Fig.2-2 Gate Charge Waveform

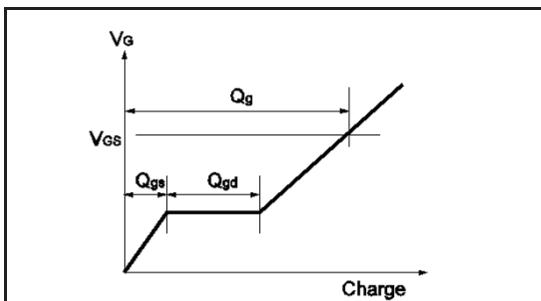


Fig.3-1 Switching Energy Measurement Circuit

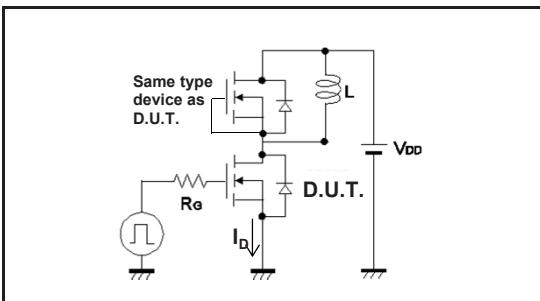


Fig.3-2 Switching Waveforms

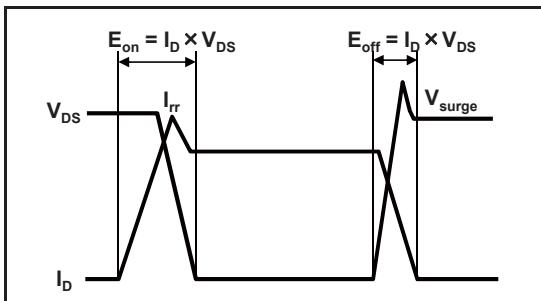


Fig.4-1 Reverse Recovery Time Measurement Circuit

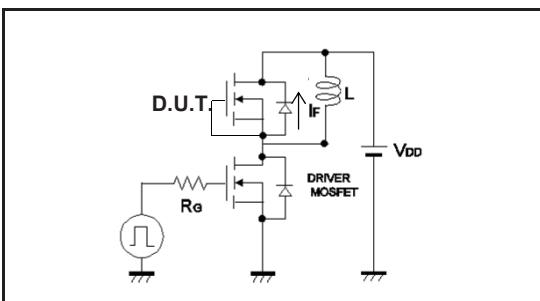


Fig.4-2 Reverse Recovery Waveform

